# Product / Process Change Notification

## N° 2012-143-A

**Dear Customer**,

Please find attached our INFINEON Technologies PCN:

## Introduction of an alternative wafer production site for products with Infineon® SSMART technology, an alternative wafer test site, an alternative tester platform for final test and minor datasheet adaption for HITFET 2nd generation latch types BTS3118D, BTS3134D, BTS3142D

Important information for your attention:

- Please respond to this PCN by indicating your decision on the approval form, sign it and return to your sales partner before 17-January 2014
- Infineon aligns with the widely-recognized JEDEC STANDARD “JESD46-C“, which stipulates: “Lack of acknowledgement of the PCN within 30 days constitutes acceptance of the change.“

Your prompt reply will help Infineon Technologies to assure a smooth and well executed transition. If Infineon does not hear from your side by the due date, we will assume your full acceptance to this proposed change and its implementation.

Your attention and response to this matter is greatly appreciated.

Disclaimer:

If we do not receive any response within the given time limit we consider this as the acceptance of the PCN.

# Product / Process Change Notification

## N° 2012-143-A

**SUBJECT OF CHANGE:**

Introduction of

- an alternative wafer production and wafer test site in Kulim for HITFET 2nd generation with SSMART technology.
- an alternative final test platform.

Minor datasheet adaptation for HITFET 2nd generation latch product types

**PRODUCTS AFFECTED:**

| Device | SP N° | OPN | Package |
|---|---|---|---|
| BTS3118D | SP000506216 | BTS3118DATMA1 | PG-TO252-3-11 |
| BTS3134D | SP000506210 | BTS3134DATMA1 | PG-TO252-3-11 |
| BTS3142D | SP000506218 | BTS3142DATMA1 | PG-TO252-3-11 |

**REASON OF CHANGE:**

Expansion of wafer production capacity for SSMART technology.
Due to continuously raising demand for Infineon automotive products we have to implement the well-known FE location Kulim as additional wafer production site and wafer test location.

Due to same reason we need to introduce an additional well established Tester platform Teradyne A565 for final BE test.

We also want to secure customer deliveries due qualification of a 2. wafer production site.

Additionally, in the course of our regular datasheet reviews we strive to keep our automotive product specifications up to date.

As a result (a) additional annotations concerning test conditions are added, (b) references to norms/regulations are updated and (c) the test condition for the input threshold voltage (VIN(th)) @ TJ=25/150°C is adapted as stated below

| **DESCRIPTION OF CHANGE:** | **production** | |
|---|---|---|
| | **Current** | **NEW** |
| **Wafer production site** | Infineon Technologies AG<br>Villach, Austria | Infineon Technologies AG<br>Villach, Austria<br><br>*Or*<br><br>Infineon Technologies AG<br>Kulim, Malaysia |

# Product / Process Change Notification

## N° 2012-143-A

| | | |
|---|---|---|
| **Wafer test site** | Infineon Technologies AG<br>Villach, Austria | Infineon Technologies AG<br>Kulim, Malaysia<br><br>*Or*<br><br>Infineon Technologies AG<br>Kulim, Malaysia |
| **Final tester platform** | Incal i9472 | Incal i9472<br><br>*Or*<br><br>Teradyne A565 |
| | | |
| **DESCRIPTION OF CHANGE:** | **datasheet** | |
| **The annotation in the form of a footnote *"not subject to production test, specified by design"* will be applied also to the following parameters** | • Maximum ratings<br>• Continuous input voltage VIN=-0.2V<br>• Electrostatic discharge voltage ESD | |
| ■ **The annotation in the form of a footnote *"not subject to production test, calculated by RthJA and Rds(on)"* will be applied also to the following parameters** | • Power dissipation Ptot<br>• Nominal load current ID(nom), ID(ISO) | |
| | **OLD** | **NEW** |
| ■ **For standardization purpose the ESD test is performed in line with the requirements of the Jedec norm** | MIL STD 883D, method 3015.7 and EOS/ESD assn. standard S5.1 -1993 | ANSI/ESDA/JEDEC JS-001 (1.5KOhm, 100pF) |
| ■ **Test condition $I_D$[mA] for parameter input threshold voltage Vin(th)**<br>o **BTS3118D**<br>o **BTS3134D**<br>o **BTS3142D** | <br>0.3mA<br>0.7mA<br>1.2mA | <br>0.6mA<br>1.4mA<br>2.4mA |

# Product / Process Change Notification

## N° 2012-143-A

**PRODUCT IDENTIFICATION:**

Wafer lot numbers from Villach start with VExxxxxx
and from Kulim with 1Exxxxxx

Traceability assured via date code.

No change in SP ordering number

**TIME SCHEDULE:**

| | |
|---|---|
| ■ Final qualification report: | available |
| ■ First samples available: | available |
| ■ Start of delivery: | June 2014 onwards<br>or earlier on customer request |
| ■ Last order date of unchanged product: | June 2014 |
| ■ Last delivery date of unchanged product: | December 2014 |

**ASSESSMENT:**

No impact on electrical performance. Quality and reliability verified by qualification.

There is no change in form, fit and function.

**DOCUMENTATION:**

2_cip12143 qualification report including AMSA study
3_cip12143 customer info package SSMART
4_cip12143 product data sheet